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PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Nakayama et al.

Application No. 10/003,042

Filed: November 13, 2001

For: METHODS AND DEVICES FOR
MEASURING A SURFACE PROFILE OF AN
OPTICAL ELEMENT

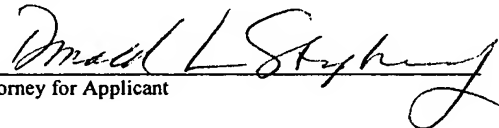
Examiner: Not yet assigned.

Date: April 19, 2002

Art Unit: Not yet assigned.

CERTIFICATE OF MAILING

I hereby certify that this paper and the documents referred to as being attached or enclosed herewith are being deposited with the United States Postal Service on April 19, 2002 as First Class Mail in an envelope addressed to: COMMISSIONER FOR PATENTS, WASHINGTON, D.C. 20231.


Attorney for Applicant

INFORMATION DISCLOSURE STATEMENT
PURSUANT TO 37 C.F.R. § 1.97(b)(3)

COMMISSIONER FOR PATENTS
WASHINGTON, DC 20231

Sir:

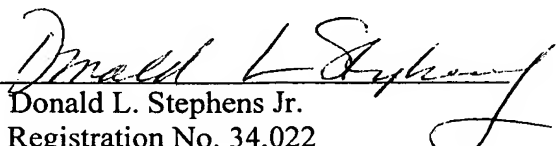
Listed on the accompanying form PTO-1449 and enclosed herewith is an English-language document. Applicants respectfully request that these documents be listed as references cited on the issued patent.

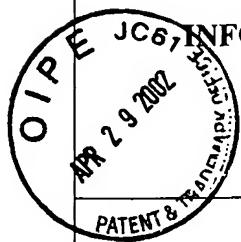
Applicants filed this Information Disclosure Statement ("IDS") before the mailing date of a first Office action on the merits. As a result, no fee should be required to file this IDS. However, if the Patent Office determines that a fee is required for Applicants to file this Information Disclosure Statement, please charge any such fees, or credit overpayment, to Deposit Account No. 02-4550. A **duplicate** copy of this Information Disclosure Statement is enclosed.

Respectfully submitted,

KLARQUIST SPARKMAN, LLP

One World Trade Center, Suite 1600
121 S.W. Salmon Street
Portland, Oregon 97204
Telephone: (503) 226-7391
Facsimile: (503) 228-9446

By 
Donald L. Stephens Jr.
Registration No. 34,022



INFORMATION DISCLOSURE STATEMENT

BY APPLICANT

Docket: 4641-61595

App: 10/003,042

Applicant: Nakayama et al.

Filed: November 13, 2001

Art Unit: Unknown

U.S. PATENT DOCUMENTS

Init.*		Number	Date	Name	Class	Sub	Filed
		5,986,760	11/16/1999	Nakayama et al.			

FOREIGN PATENT DOCUMENTS

		Number	Date	Country	Class	Sub	

OTHER DOCUMENTS

EXAMINER:

DATE

*Examiner: Initial if considered, whether or not in conformance with MPEP 609; draw line through cite if not in conformance and not considered. Send copy.